

Wet etching technique for fabrication of GaSb based mid infrared single lateral mode lasers

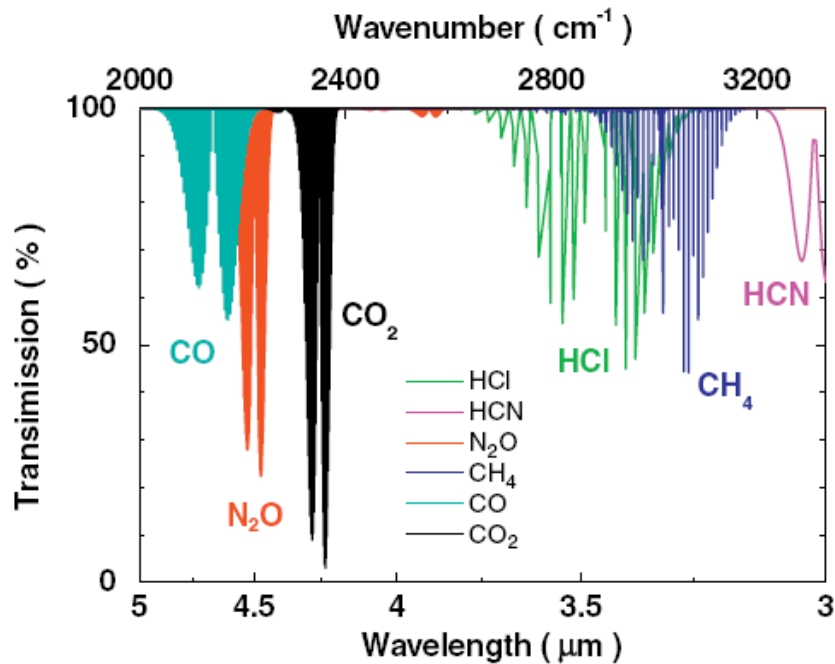
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Leon Shterengas, Gela Kipshidze,
and Gregory Belenky

06.24.2011

Outline

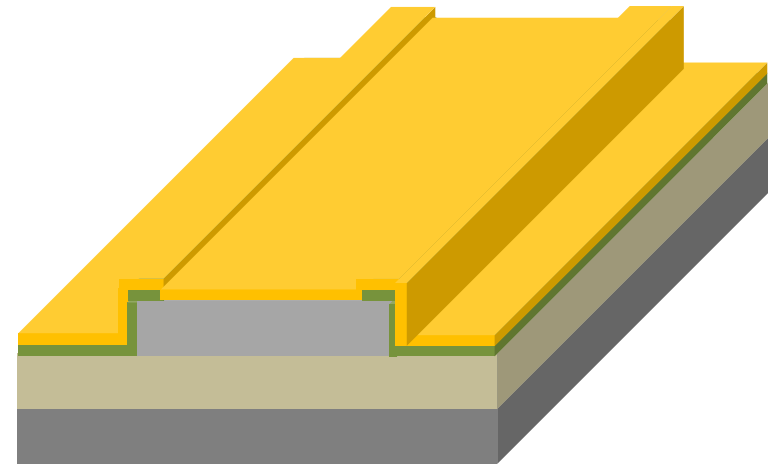
- Motivation
- Technology description
- Device fabrication
- Result and discussion
- Summary

Applications of Mid IR Lasers



A. Krier et al, *phys. stat. sol. (a)* 205, No. 1, 129–143 (2008)

Absorption spectra of various gases
within Mid IR ($2 \sim 5 \mu\text{m}$) range

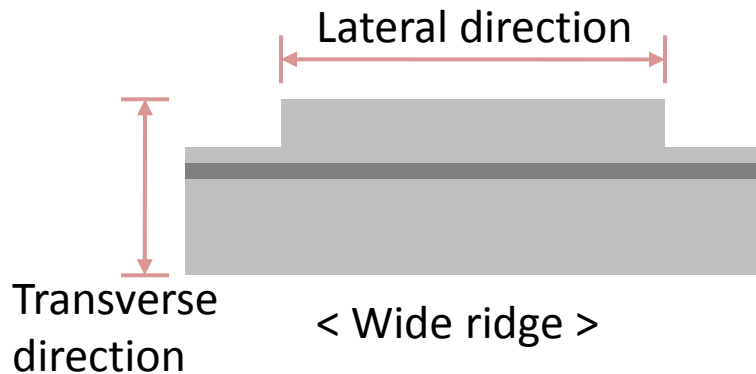


<Schematic of the narrow ridge laser>

<Applications>

- Gas detection
- Free space communication
- Medical diagnostics

Wide ridge vs. Narrow ridge lasers



Characteristics

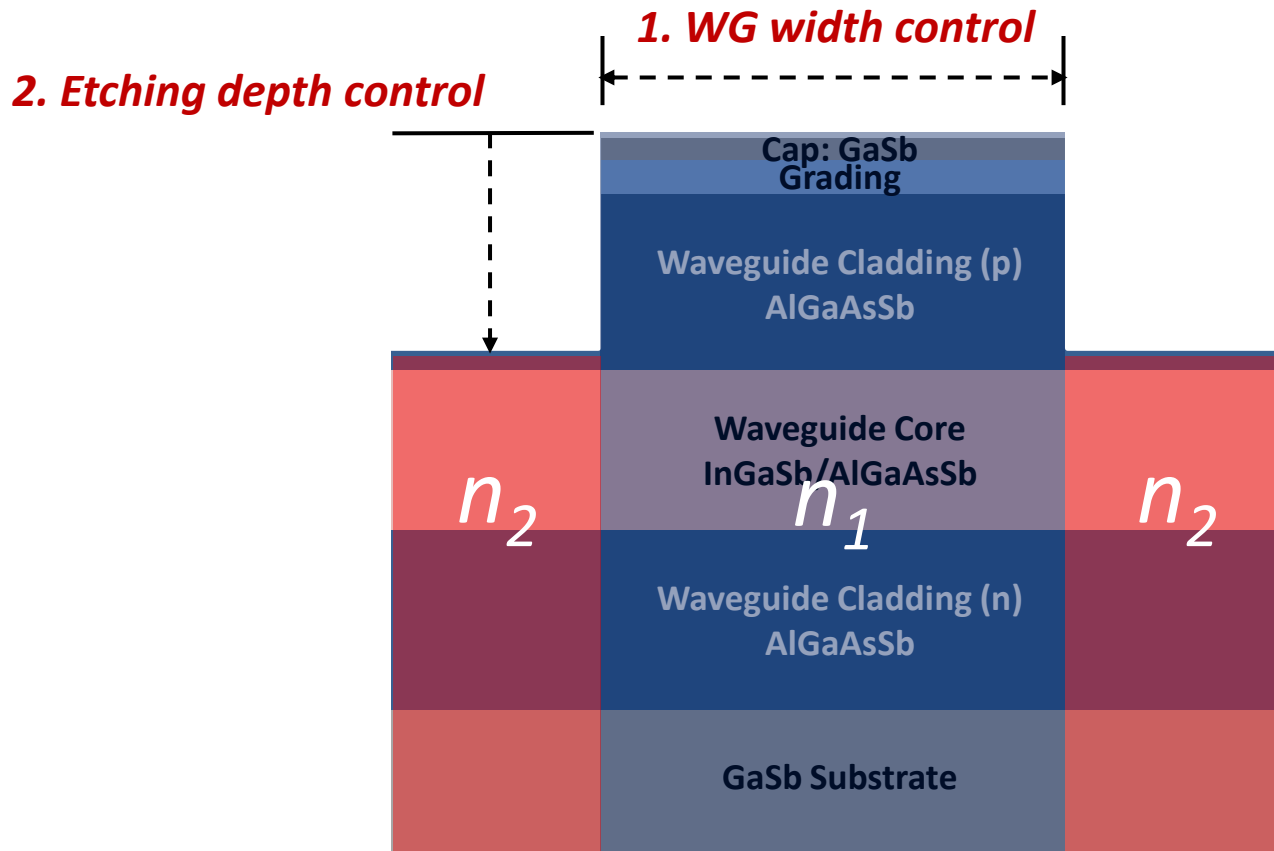
- Wide mesa width $\sim 100 \mu\text{m}$
- High power
- Lateral multimode operation
- Relatively easy fabrication



Characteristics

- Narrow mesa width $< 10 \mu\text{m}$
- Low threshold
- Lateral single mode operation
- Relatively difficult fabrication
- Necessary step for the longitudinal single mode operation

Crucial points to fabricate the narrow ridge



< Typical GaSb based mid IR laser QW laser structure >

Lateral single mode requires the precise refractive index step (n_1-n_2) control together with the mesa width.0

Fabrication of narrow ridge

<Dry etching>

Advantages

- Precise control of etching depth
- High degree of Directivity
- High degree of non-selective etching

Disadvantages

- High cost
- Low throughput

<Wet etching>

Advantages

- Cost effective
- High throughput
- Relatively easy implementation
- High degree of material selectivity

Disadvantages

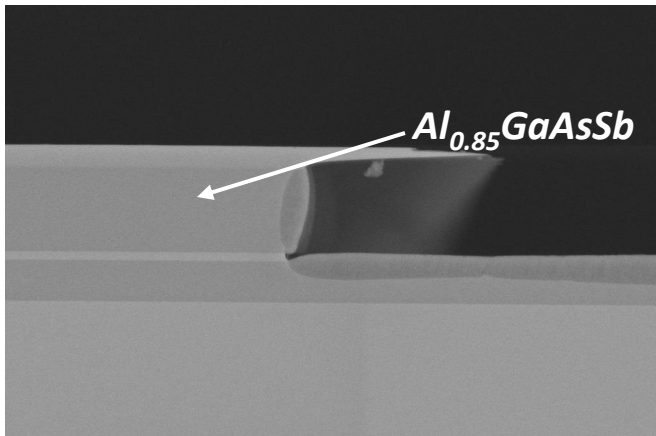
- Low degree of directivity
- High degree of material selectivity



Could be preferred to industrial process.

Implementation challenges using wet etching

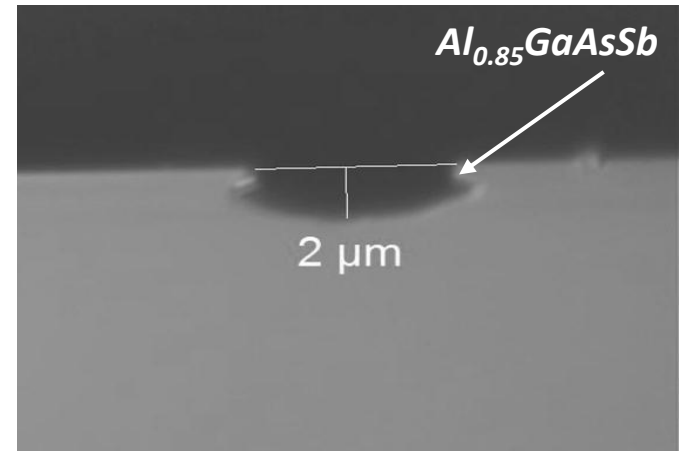
Material selectivity



< Etching test with **HCl** based solution >

→ *Fast etching rate for Al-rich material*

Isotropic etching profile



< Etching test with **Tartrate** based solution >

→ *Fast etching rate for non Al-rich material*

Two major points of this technique

Complementary Etching

- Role:
To compensate etching selectivity between the GaSb and AlGaAsSb layer.
- Procedure:
 - 1. Etching GaSb with Tartrate solution***
 - 2. Etching AlGaAsSb with HCl solution***

Etch Stopper

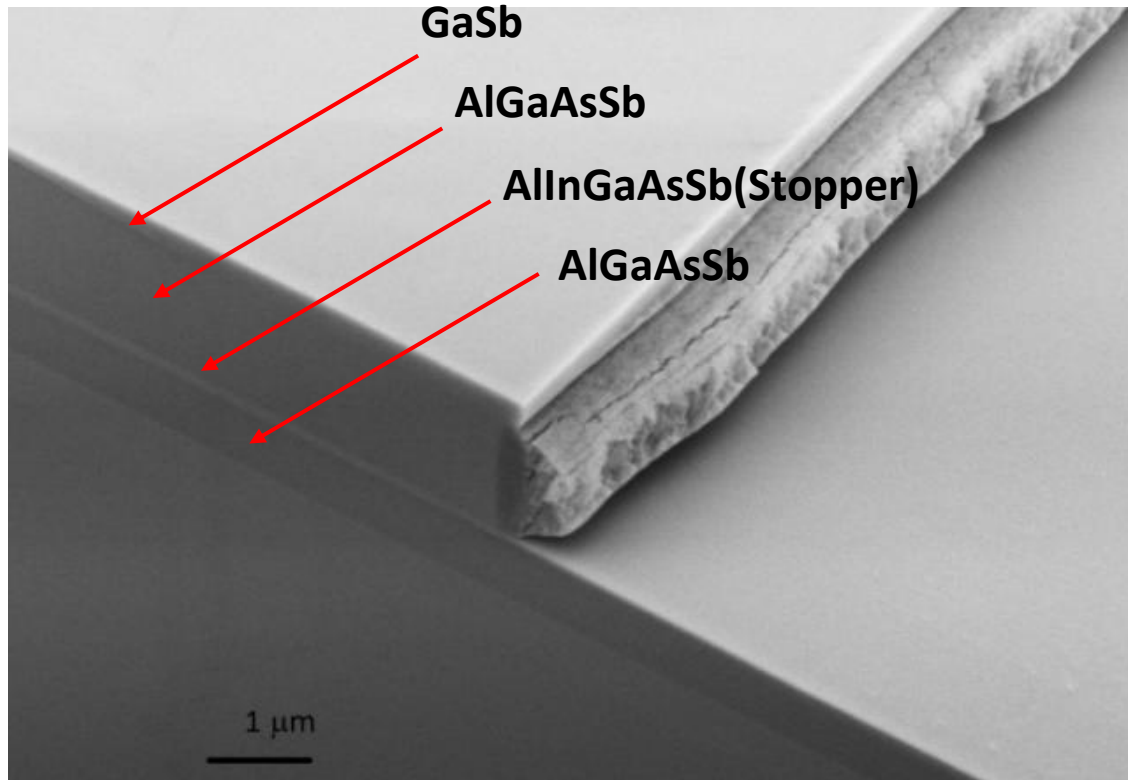
- Role:
To control precise etching depth
- Requirement:
 1. Slow etching rate with HCl
 2. Need to minimize carrier transport problem

Proper material selection



AllnGaAsSb

Preliminary wet etching result



<Etching test with the etch stopper>

Processing detail: Etchant preparation

<Tartrate based solution>

Tartrate : DI Water : H₂O₂ : H₃PO₄
= 5 g : 90 ml : 30 ml : 30 ml



Under stirring for 2 days

<HCl based solution>

HCl : DI Water : H₂O₂
= 50 ml : 50 ml : 1 ml



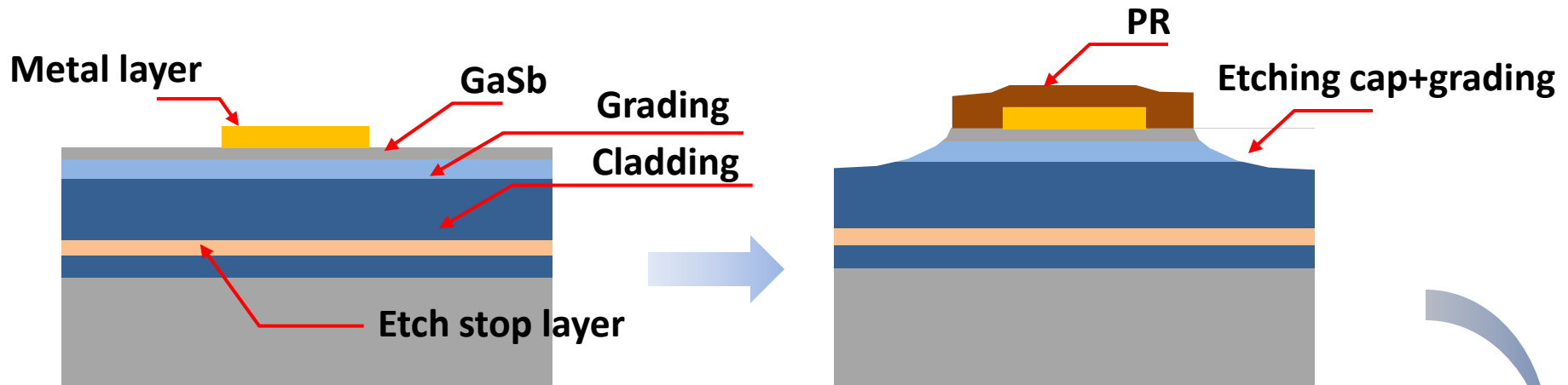
H₂O₂ was added just before used.

<Etching rate of etch etchant>

| <i>Material</i> | <i>GaSb</i> | <i>AlGaAsSb</i> | <i>AllnGaAsSb</i> |
|--|-------------|-----------------|---------------------|
| <i>Role</i> | <i>Cap</i> | <i>Cladding</i> | <i>Etch stopper</i> |
| <i>Etching rate of Tartrate (nm/sec)</i> | 16.6 | 5 | - |
| <i>Etching rate of HCl (nm/sec)</i> | 3.2 | 30 | 1.1 |

Highly selective!

Processing detail: Etching Procedure

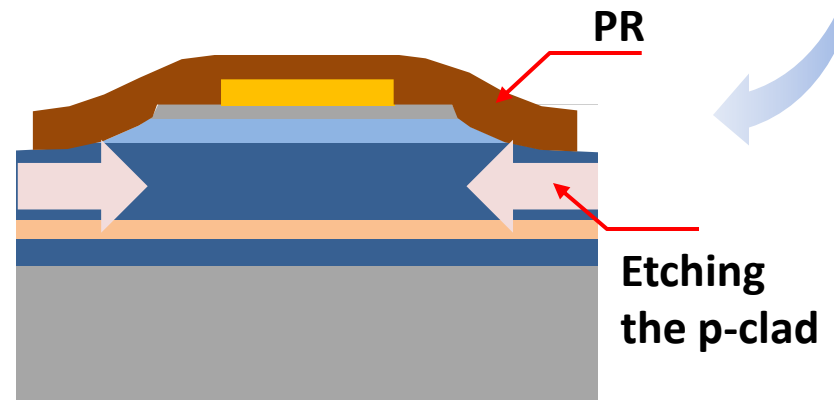


<1. Metal deposition>

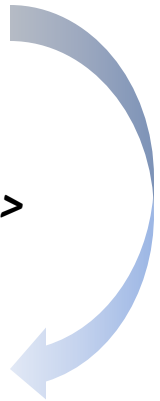


<4. Photo-resist removal>

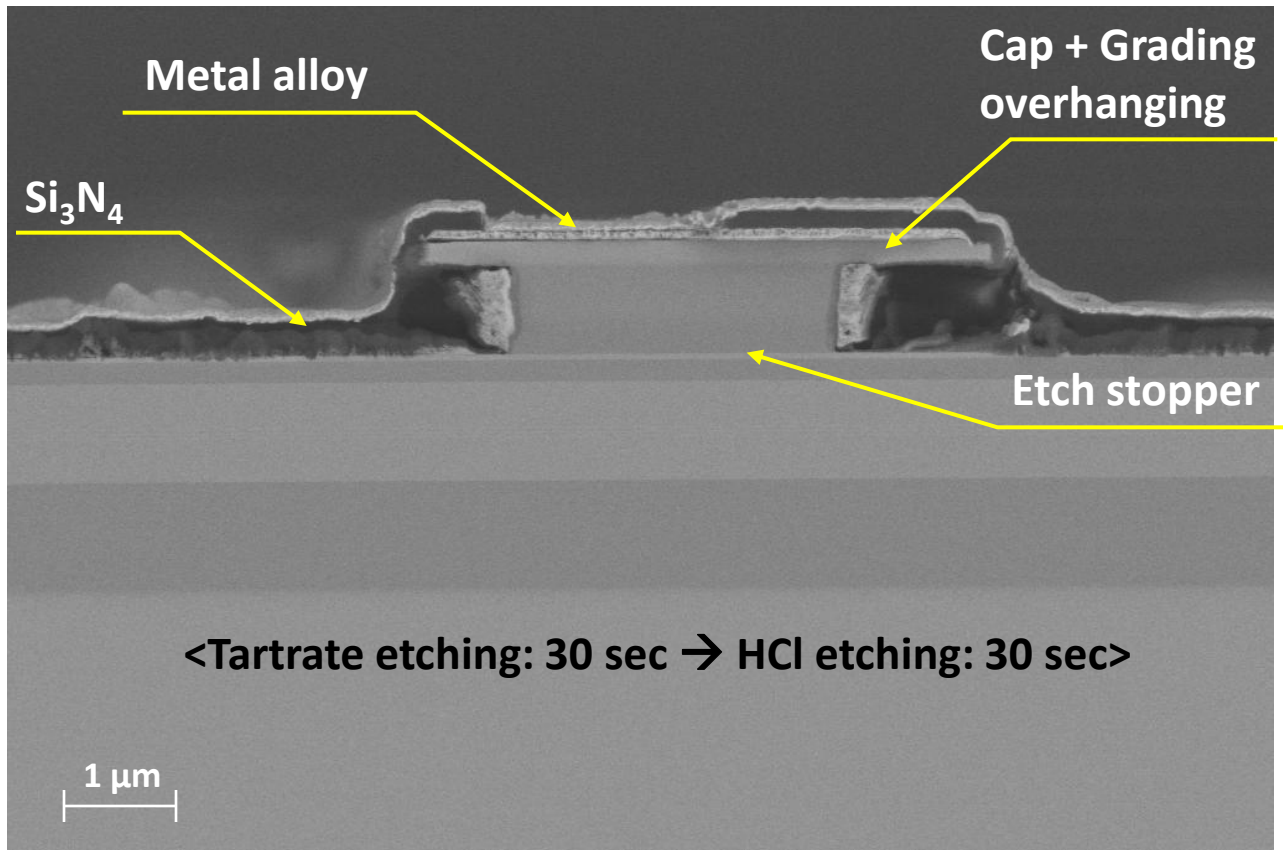
<2. Etching with the Tartrate solution>



<3. Etching with the HCl solution>

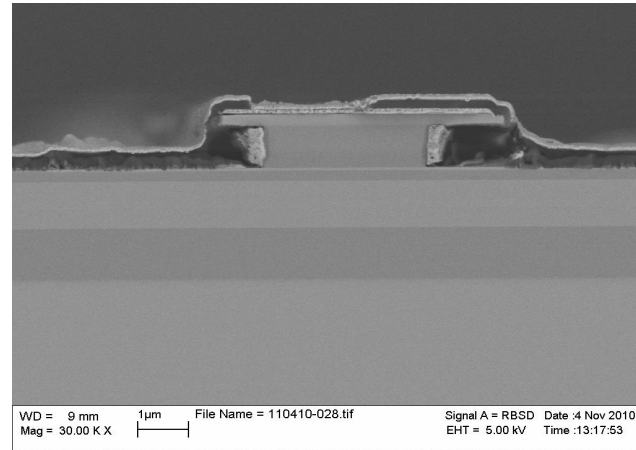
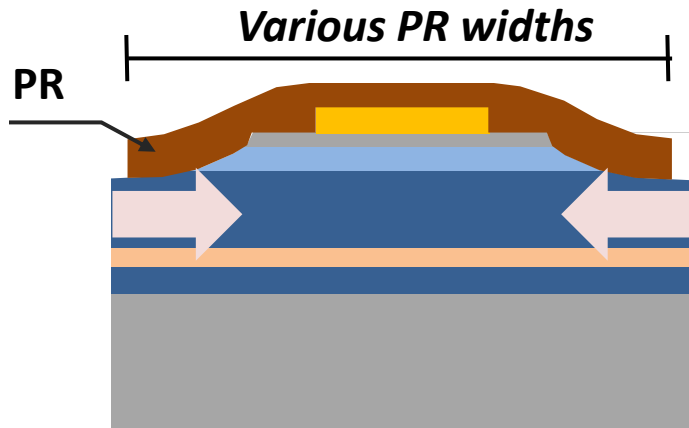


Vertical wall narrow ridge with wet etching

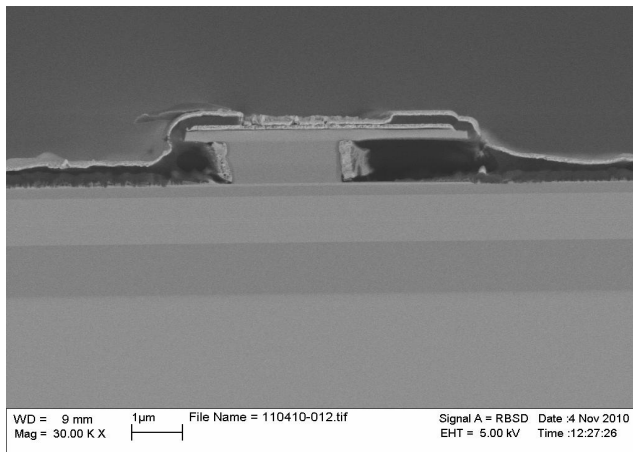


< SEM image of the complete laser device >

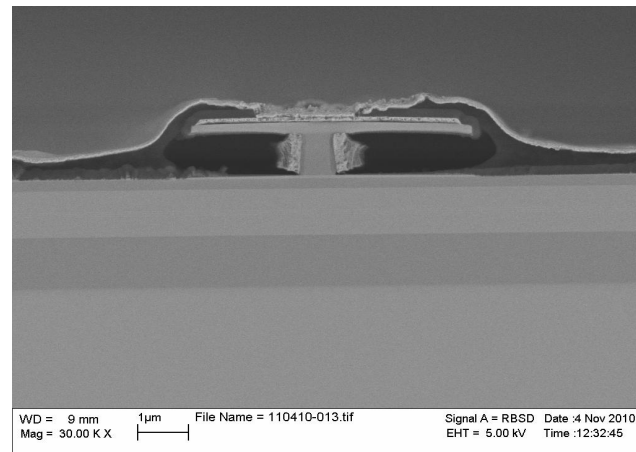
Mesa width control



<4.2 μm (12 μm)>

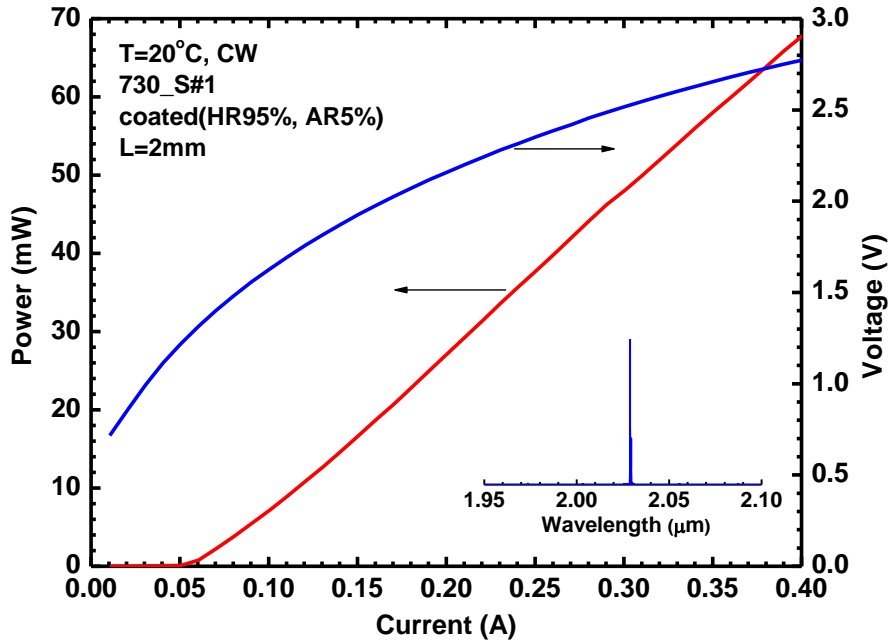


<2.4 μm (10 μm)>

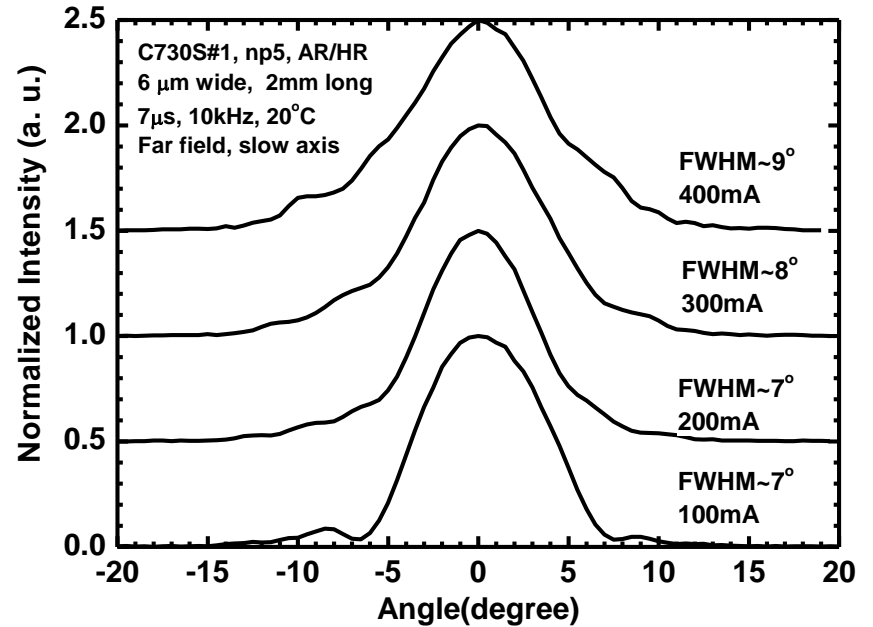


<0.5 μm (8 μm)>

Laser performance



RT cw power: ~70mW



Far field at slow axis: ~8° (FWHM)

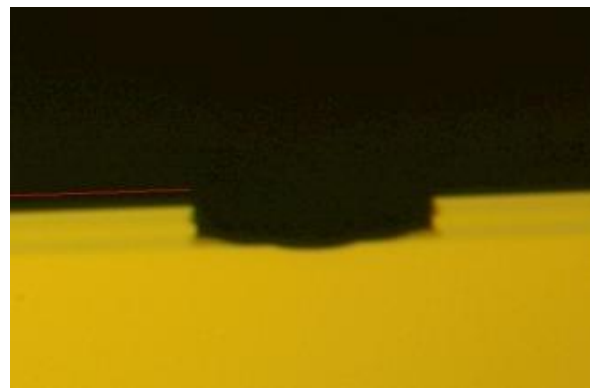
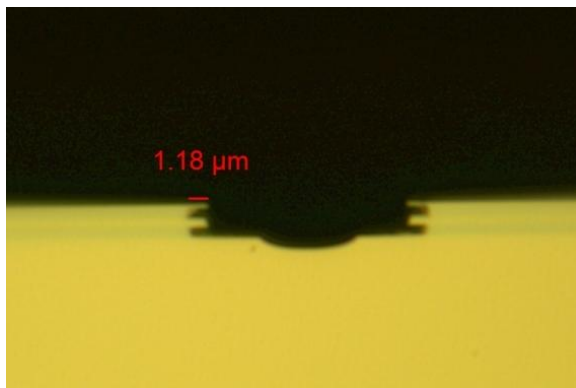
Summary and Future work

<Summary>

- *The lateral single mode laser has been fabricated by cost effective wet etching technique.*
- *Complementary etching with the etch stopper demonstrated effective mesa width and etching depth control.*
- *This technique can be used for sidewall smoothing, standing free 2D wire, etc. consisting of Al-rich and InGaAsSb sequential layers.*

< Future work >

- *Optimization of the etching process for precise etching control.*



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